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|-----------------------------------|--|-------------------------|---|--|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination | |
| | | 10/043,587 | ZETTEL, STEVEN | |
| Examiner Hien Tran | | Art Unit 1764 | Page 1 of 1 | |

U.S. PATENT DOCUMENTS

| * | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|--|-----------------|---------------------|----------------|
| A | US-3,876,384 | 04-1975 | Santiago et al. | 422/179 |
| B | US-4,278,717 | 07-1981 | Aoyama, Toshiho | 422/179 |
| C | US-4,818,257 | 04-1989 | Kennedy et al. | 95/286 |
| D | US-5,449,500 | 09-1995 | Zettel, Steven | 422/179 |
| E | US-5,686,039 | 11-1997 | Merry, Richard P. | 264/259 |
| F | US-5,866,079 | 02-1999 | Machida et al. | 422/179 |
| G | US-6,017,498 | 01-2000 | Harding, Raymond C. | 422/179 |
| H | US- | | | |
| I | US- | | | |
| J | US- | | | |
| K | US- | | | |
| L | US- | | | |
| M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|--|-----------------|---------|--------------|----------------|
| N | EP 1,138,892 | 10-2001 | EP | Yamada et al | --- |
| O | | | | | |
| P | | | | | |
| Q | | | | | |
| R | | | | | |
| S | | | | | |
| T | | | | | |

NON-PATENT DOCUMENTS

| | | | |
|---|---|--|--|
| * | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) | | |
| U | | | |
| V | | | |
| W | | | |
| X | | | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.